REVISIONS

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED

REV											
SHEET											
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REV STATUS OF SHEETS	REV										
	SHEET	1	2	3	4	5	6	7	8	9	10

PMIC N/A

STANDARDIZED MILITARY DRAWING

THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE

AMSC N/A

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DRAWING APPROVAL DATE
24 FEBRUARY 1988

REVISION LEVEL

DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

MICROCIRCUIT, DIGITAL, BIPOLAR, ADVANCED SCHOTTKY TTL, 2 INPUT AND DRIVERS, MONOLITHIC SILICON

SIZE	CAGE CODE	
A	67268	5962-88522

SHEET 1 OF 10

DESC FORM 193
SEP 87

U.S. GOVERNMENT PRINTING OFFICE: 1987 — 748-129/60911

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:

5962-88522	01	R	X
Drawing number	Device type (1.2.1)	Case outline (1.2.2)	Lead finish per MIL-M-38510

1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	54AS808	Hex 2-input AND drivers

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	Case outline
R	D-8 (20-lead, 1.060" x .310" x .200"), dual-in-line package
S	F-9 (20-lead, .540" x .300" x .100"), flat package
2	C-2 (20-terminal, .358" x .358" x .100"), square chip carrier package

1.3 Absolute maximum ratings.

Supply voltage range (V_{CC}) - - - - - - - - - - - - - - -	-0.5 V dc minimum to +7.0 V dc maximum
Input voltage range - - - - - - - - - - - - - - - - - -	-1.2 V dc at -18 mA to +7.0 V dc
Storage temperature range - - - - - - - - - - - - - - -	-65°C to +150°C
Maximum power dissipation, (P_D) 1/- - - - - - - - - - -	+182 mW
Lead temperature (soldering, 10 seconds) - - - - - - -	+300°C
Thermal resistance, junction-to-case (Θ_{JC})- - - - - -	See MIL-M-38510, appendix C
Junction temperature (T_J) - - - - - - - - - - - - - -	+175°C

1.4 Recommended operating conditions.

Supply voltage range (V_{CC}) - - - - - - - - - - - - - -	+4.5 V dc minimum to +5.5 V dc maximum
Minimum high level input voltage (V_{IH})- - - - - - - - -	2.0 V dc
Maximum low level input voltage (V_{IL}) - - - - - - - - -	0.8 V dc
Case operating temperature range (T_C) - - - - - - - - -	-55°C to +125°C

1/ Must withstand the added P_D due to short circuit test, e.g., I_O.

2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Truth table. The truth table shall be as specified on figure 2.

3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.

3.2.4 Waveforms and test circuit. The waveforms and test circuit shall be as specified on figure 4.

3.2.5 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.

3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions 1/ $-55^{\circ}C \leq T_C \leq +125^{\circ}C$ unless otherwise specified		Group A subgroups	Limits		Unit
					Min	Max	
High level output voltage	V_{OH}	V_{CC} = 4.5 V V_{IL} = 0.8 V V_{IH} = 2.0 V 2/	I_{OH} = -2.0 mA	1,2,3	2.5		V
			I_{OH} = -3.0 mA		2.4		
			I_{OH} = -40.0 mA		2.0		
Low level output voltage	V_{OL}	V_{CC} = 4.5 V V_{IL} = 0.8 V V_{IH} = 2.0 V	2/ I_{OL} = 40 mA	1,2,3		0.5	V
Input clamp voltage	V_{IC}	V_{CC} = 4.5 V	I_{IN} = -18 mA	1,2,3		-1.2	V
Low level input current	I_{IL}	V_{CC} = 5.5 V V_{IL} = 0.4 V	Inputs not under test = 4.5 V	1,2,3		-0.5	mA
High level input current	I_{IH1}	V_{CC} = 5.5 V V_{IH} = 2.7 V	Inputs not under test = 0.0 V	1,2,3		20	µA
	I_{IH2}	V_{CC} = 5.5 V V_{IH} = 7.0 V				0.1	mA
Output current	I_O	V_{CC} = 5.5 V V_{OUT} = 2.25 V	3/	1,2,3	-50	-200	mA
Supply current	I_{CCH}	V_{CC} = 5.5 V V_{IN} = 4.5 V		1,2,3		13	mA
	I_{CCL}	V_{CC} = 5.5 V V_{IN} = 0.0 V				33	
Functional tests		See 4.3.1c		7			
Propagation delay time A, B to Y	t_{PLH}	V_{CC} = 4.5 V to 5.5 V C_L = 50 pF ±10% R_L = 500Ω ±5% See figure 4	4/	9,10,11	1	6.5	ns
	t_{PHL}			9,10,11	1	6.5	ns

1/ Unused inputs that do not directly control the pin under test must be $\geq$ 2.5 V or $\leq$ 0.4 V, but shall not exceed 5.5 V or go less than 0.0 V and no inputs shall be floated.

2/ All outputs must be tested. In the case where only one input at V_{IL} maximum or V_{IH} minimum produces the proper output state, the test must be performed with each input being selected as the V_{IL} maximum or V_{IH} minimum input.

3/ The output conditions have been chosen to produce a current that closely approximates one half of the true short circuit output current, I_{OS}. Not more than one output will be tested at one time and the duration of the test condition shall not exceed one second.

4/ Propagation delay limits are based on single output switching. Unused outputs = 3.5 V or $\leq$ 0.3 V.

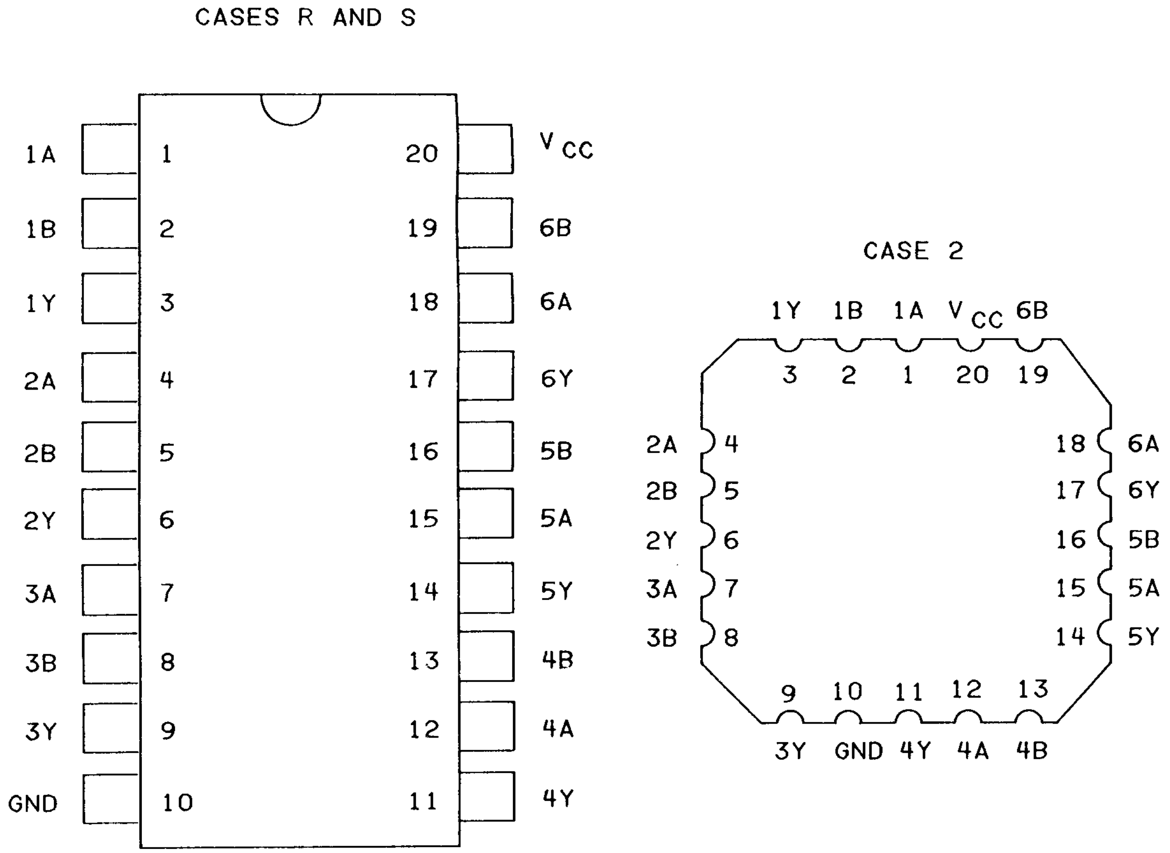


FIGURE 1. Terminal connections.

Inputs		Outputs
A	B	Y
H	H	H
L	X	L
X	L	L

H = High level
L = Low level
X = Irrelevant

FIGURE 2. Truth table (each driver).

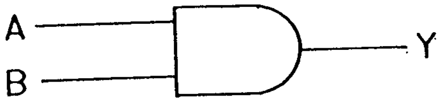
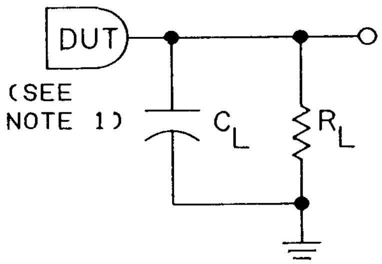
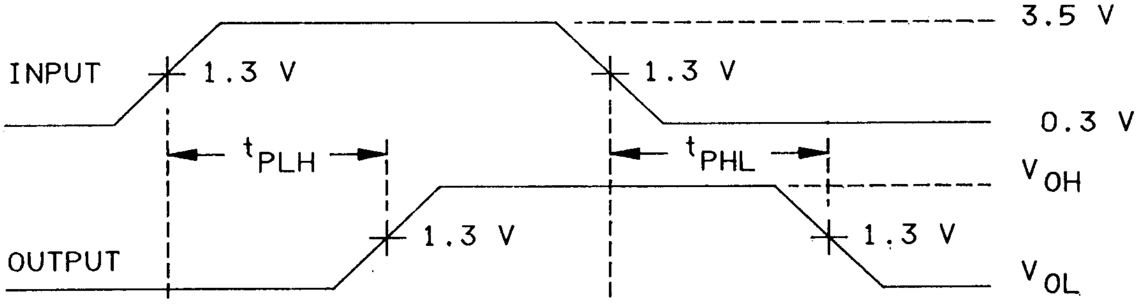


FIGURE 3. Logic diagram (each driver).



TEST CIRCUIT



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

NOTES:
1. C_L includes probe and jig capacitance.
2. All input pulses have the following characteristics: PRR $\leq$ 10 MHz, duty cycle = 50 percent, $t_r = t_f = 3$ ns ±1 ns.
3. The outputs are measured one at a time with one input transition per measurement.

FIGURE 4. Waveforms and test circuit.

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3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

    (1) Test condition A or D using the circuit submitted with the certificate of compliance (see 3.5 herein).

    (2) T_A = +125°C, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 4, 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.

c. Subgroup 7 tests shall verify the truth table as specified on figure 2 herein.

4.3.2 Groups C and D inspections.

a. End-point electrical parameters shall be as specified in table II herein.

b. Steady-state life test conditions, method 1005 of MIL-STD-883:

    (1) Test condition A or D using the circuit submitted with the certificate of compliance (see 3.5 herein).

    (2) T_A = +125°C, minimum.

    (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*, 2, 3, 7, 9, 10, 11
Group A test requirements (method 5005)	1, 2, 3, 7, 9, 10, 11
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

* PDA applies to subgroup 1.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

6.4 Approved sources of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number 1/
5962-8852201RX	01295	SNJ54AS808BJ
5962-8852201SX	01295	SNJ54AS808BW
5962-88522012X	01295	SNJ54AS808BFK

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number	Vendor name and address
01295	Texas Instruments, Incorporated P.O. Box 6448 Midland, TX 79711

011254 ✓